National Aeronautics and Space Administration



TBD

High Temperature / High Frequency Temperature Measurement: Achieving MHz response at Temperatures > 1000 deg-F

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EXECUTIVE SUMMARY

High frequency temperature measurements are not possible with current SOA temperature measurement devices at temperatures higher than ~700 deg-F. Temperature measurements above ~1000 deg-F are typical for entry vehicle thermal protection systems (TPS), rocket engines, ram/scramjet engines, etc. A new technology capable of achieving ~1200 deg-F temperature measurements with MHz response has been achieved. Investigations are underway to extend the concept to even higher temperatures.

U.S. Patent Application submitted (Patent Pending: #63/599,787).

INNOVATION

High temperature materials typical of entry vehicle TPS, rocket engine internal components, ramjet and scramjet nozzle surfaces, etc can induce very large thermo-mechanical stress and strain due to high temperature gradients and differing coefficients of thermal expansion (CTE). So called CTE mismatch is a design consideration for all thin surface coatings and was identified through demonstration to be a large contributing factor in failure of thin-film temperature measurement devices. High frequency temperature measurements motivate for the use of very thin temperature measurement devices. The innovation involves addressing the CTE mismatch and stress/strain concentrations that occur between the typical larger diameter electrical lead wires, and the thin-film desired for high frequency response.



Platinum Thin-Film on RCG Investigations Scanning Electron Microscope

COLLABORATION





Engineering Directorate ES3 Materials Lab

Development History

- 2011 MHz capable Platinum (Pt) RTD applied to Orbiter RCG
- tile. Open circuit near 900 deg-F experienced on cool-down.
- 2015 Concept for relieving CTE effects documented
- 2016 Innovation Disclosure submitted
- 2019 MHz capable Pt RTD application on Pyrex substrate Joint NASA/Cubrc Innovation Disclosure
- 2021 JSC Innovation Board approved patent pursuit Supported by market survey demonstrating interest Innovation Office \$ approved to develop patent application
- 2022 Pt Sputtered thin-film absorbed/dispersed into RCG above 1000 deg-F; SEM & EDS results
- 2023 Lab investigations of fumed silica based buffer layer Final updates to patent application prepared
 - U.S. Patent submission imminent



Benchtop RCG Investigations of Pt thin-film supported by ES3/Materials Lab, Mike Fowler/ES, Frank Samonski/JESC

Fumed Silica on RCG Investigations

Xerogel Trials with Acetone:Fumed Silica / Volumetric Ratio 1:2







Ambient Cured

Glass Fiber Reinforced 1:4 Glass Fiber Reinforced 1:4 Ambient Cured Enclosure Cured

Desired Fumed Silica Buffer Layer Achieved with Enclosure Cured 2:1 Xerogel and 1:4 Glass Fiber

OUTCOMES & INFUSION

- Concept for relieving high temperature thermal expansion (CTE) effects on thin-film connection to lead wires validated
- Key aspects of innovation include: transverse wire wrap relative to thin-film, colloidal Platinum bridging of wire to thin film, channel cut for wire wrap to enable manufacture, channel back-fill with ceramic adhesive for robustness
- >1200 deg-F, MHz capable Resistance Temperature Device (RTD)
 - SOA capability is currently about 700 deg-F

Original 2019 Cubrc Prototype RTD on Pyrex





- New device TRL ~5 (relevant lab environment)
- Straight-forward extensibility to TRL 9 with flight test
- U.S. Patent application in-work

FUTURE WORK

Utilize Glass Fiber/Xerogel buffer layer on RCG, attempt Pt RTD fabrication
Upon Patent filing, increase visibility for potential ground test / flight utilization for TRL advancement



